

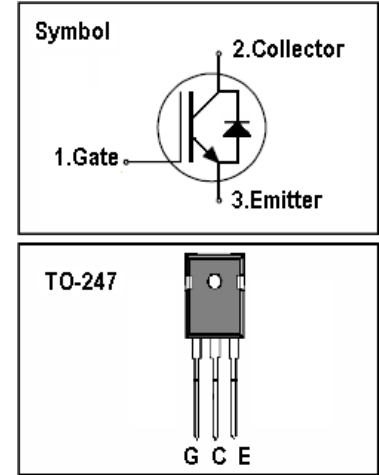
## IGBT

### Features

- 1200V,25A
- $V_{CE(sat)}(typ.)=2.0V@V_{GE}=15V,I_C=25A$
- High speed switching
- Higher system efficiency
- Soft current turn-off waveforms
- Square RBSOA

### General Description

JIAEN Trench IGBTs offer lower losses and higher energy efficiency for application such as IH (induction heating),UPS, general inverter and other soft switching applications.



### Absolute Maximum Ratings

Symbol	Parameter	Value	Units
$V_{CES}$	Collector-Emitter Voltage	1200	V
$V_{GES}$	Gate-Emitter Voltage	$\pm 30$	V
$I_C$	Continuous Collector Current ( $T_C=25^\circ C$ )	50	A
	Continuous Collector Current ( $T_C=100^\circ C$ )	25	A
$I_{CM}$	Pulsed Collector Current (Note 1)	75	A
$I_F$	Diode Continuous Forward Current ( $T_C=100^\circ C$ )	25	A
$I_{FM}$	Diode Maximum Forward Current (Note 1)	75	A
$t_{sc}$	Short Circuit Withstand Time	10	us
$P_D$	Maximum Power Dissipation ( $T_C=25^\circ C$ )	275	W
	Maximum Power Dissipation ( $T_C=100^\circ C$ )	110	W
$T_J$	Operating Junction Temperature Range	-55~150	$^\circ C$
$T_{STG}$	Storage Temperature Range	-55~150	$^\circ C$

### Thermal Characteristics

Symbol	Parameter	Max.	Units
$R_{th j-c}$	Thermal Resistance, Junction to case for IGBT	0.45	$^\circ C/W$
$R_{th j-c}$	Thermal Resistance, Junction to case for Diode	1.5	$^\circ C/W$
$R_{th j-a}$	Thermal Resistance, Junction to Ambient	40	$^\circ C/W$

## Electrical Characteristics (T<sub>C</sub>=25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
BV <sub>CES</sub>	Collector-Emitter Breakdown Voltage	V <sub>GE</sub> = 0V, I <sub>C</sub> = 250uA	1200	-	-	V
I <sub>CES</sub>	Collector-Emitter Leakage Current	V <sub>CE</sub> = 1200V, V <sub>GE</sub> = 0V	-	-	100	uA
I <sub>GES</sub>	Gate Leakage Current, Forward	V <sub>GE</sub> =30V, V <sub>CE</sub> = 0V	-	-	100	nA
	Gate Leakage Current, Reverse	V <sub>GE</sub> = -30V, V <sub>CE</sub> = 0V	-	-	100	nA
V <sub>GE(th)</sub>	Gate Threshold Voltage	V <sub>GE</sub> = V <sub>CE</sub> , I <sub>C</sub> = 250uA	4.5	-	6.5	V
V <sub>CE(sat)</sub>	Collector-Emitter Saturation Voltage	V <sub>GE</sub> =15V, I <sub>C</sub> = 25A	-	2.0		V
Q <sub>g</sub>	Total Gate Charge	V <sub>CC</sub> =960V V <sub>GE</sub> =15V I <sub>C</sub> =15A	-	81		nC
Q <sub>ge</sub>	Gate-Emitter Charge		-	24.3		nC
Q <sub>gc</sub>	Gate-Collector Charge		-	44.7		nC
t <sub>d(on)</sub>	Turn-on Delay Time	V <sub>CC</sub> =600V V <sub>GE</sub> =15V I <sub>C</sub> =25A R <sub>G</sub> =15Ω Inductive Load T <sub>C</sub> =25 °C	-	32	-	ns
t <sub>r</sub>	Turn-on Rise Time		-	50	-	ns
t <sub>d(off)</sub>	Turn-off Delay Time		-	157	-	ns
t <sub>f</sub>	Turn-off Fall Time		-	70	-	ns
E <sub>on</sub>	Turn-on Switching Loss		-	1.27	-	mJ
E <sub>off</sub>	Turn-off Switching Loss		-	0.82	-	mJ
E <sub>ts</sub>	Total Switching Loss		-	2.09	-	mJ
C <sub>ies</sub>	Input Capacitance	V <sub>CE</sub> =25V	-	1665	-	pF
C <sub>oes</sub>	Output Capacitance	V <sub>GE</sub> =0V	-	79.6	-	pF
C <sub>res</sub>	Reverse Transfer Capacitance	f = 1MHz	-	14.7	-	pF

## Electrical Characteristics of Diode (T<sub>C</sub>=25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
V <sub>F</sub>	Diode Forward Voltage	I <sub>F</sub> =25A	-	2.15	2.8	V
t <sub>rr</sub>	Diode Reverse Recovery Time	V <sub>CE</sub> = 600V	-	182		ns
I <sub>rr</sub>	Diode peak Reverse Recovery Current	I <sub>F</sub> = 25A	-	20		A
Q <sub>rr</sub>	Diode Reverse Recovery Charge	R <sub>G</sub> =15 Ω	-	1328		nC

### Notes:

1. Repetitive Rating: Pulse width limited by maximum junction temperature

## Typical Performance Characteristics

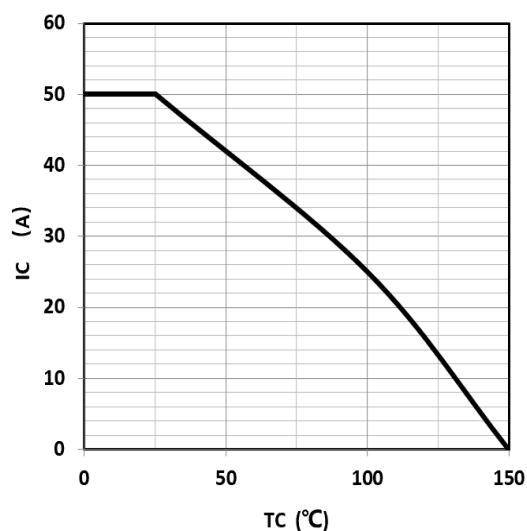


Figure 1. maximum DC collector current  
VS. case temprature

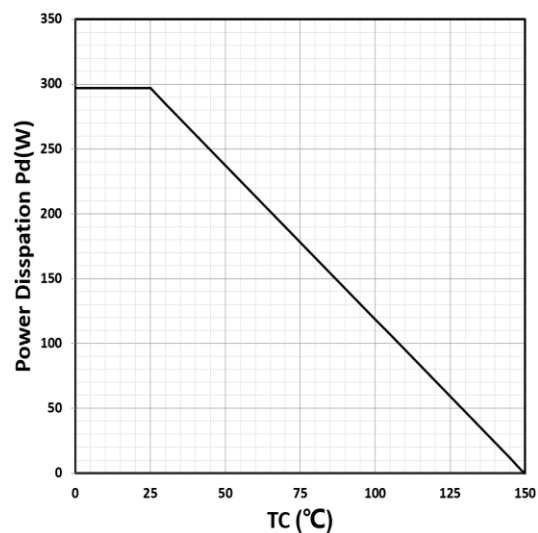


Figure 2. power dissipation VS. case temprature

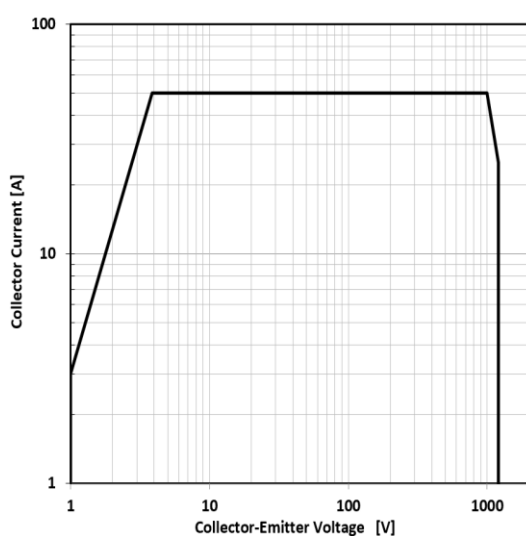


Figure 3. Reverse bias SOA, TJ=125°C, VGE=15V

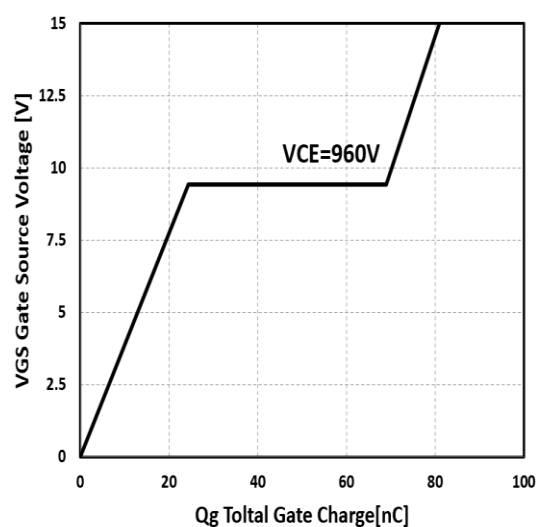


Figure 4. Typical gate charge VS. VGE, IC=25A

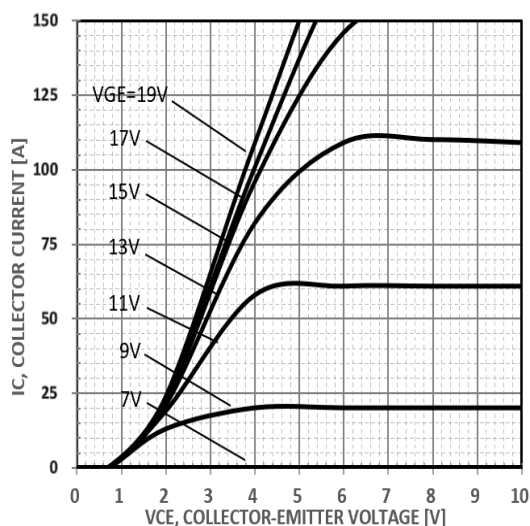


Figure 5. typical IGBT output characteristics,  
 $T_J=25^{\circ}\text{C}$ ;  $t_p=300\mu\text{s}$

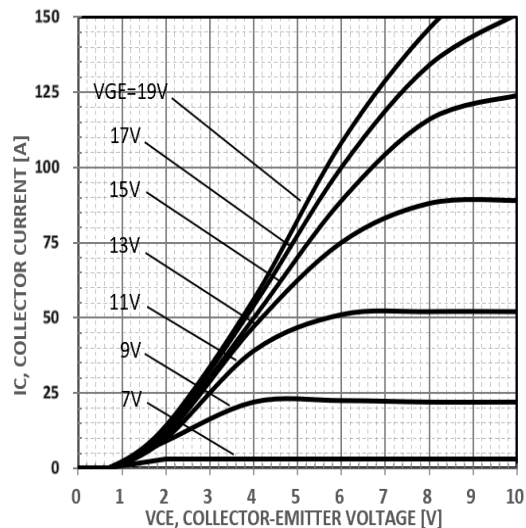


Figure 6. typical IGBT output characteristics,  
 $T_J=150^{\circ}\text{C}$ ;  $t_p=300\mu\text{s}$

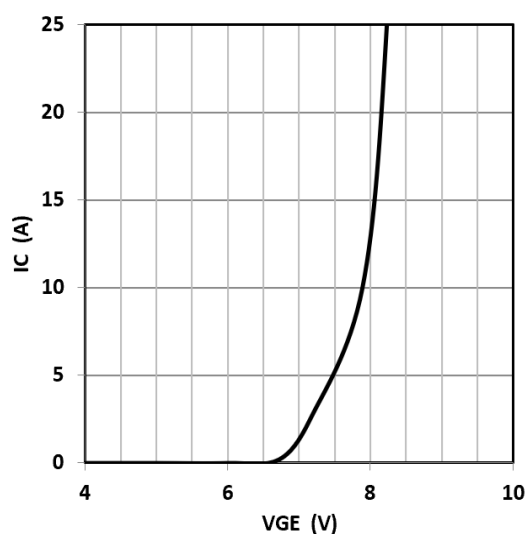


Figure 7. Typical gate threshold voltage

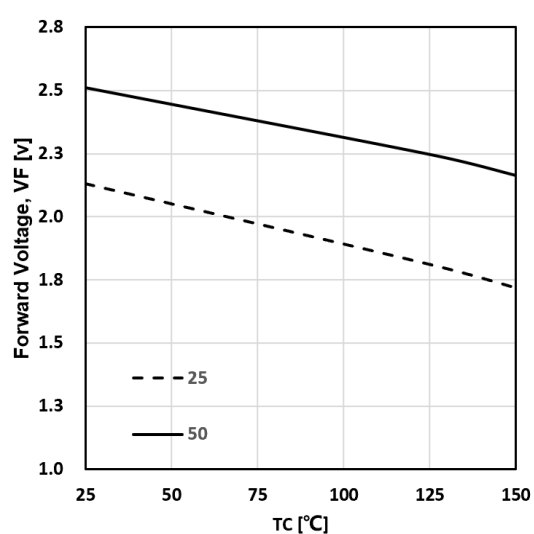


Figure 8. Typical forward voltage vs  $T_c$

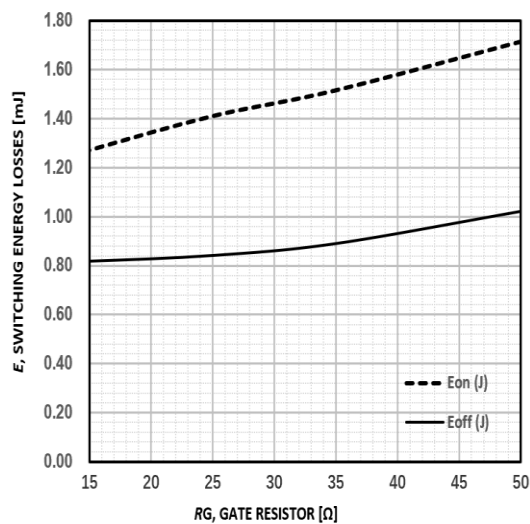


Figure 9. Typical energy loss VS.  $R_g$ ,  $T_C=25^\circ\text{C}$ ,  
 $V_{CE}=600\text{V}$ ,  $V_{GE}=15\text{V}$ ,  $I_C=25\text{A}$

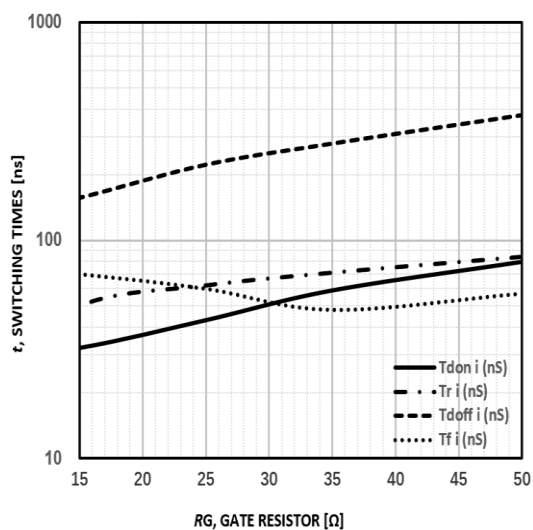


Figure 10. Typical switching time VS.  $R_g$ ,  $T_C=25^\circ\text{C}$ ,  
 $V_{CE}=600\text{V}$ ,  $V_{GE}=15\text{V}$ ,  $I_C=25\text{A}$

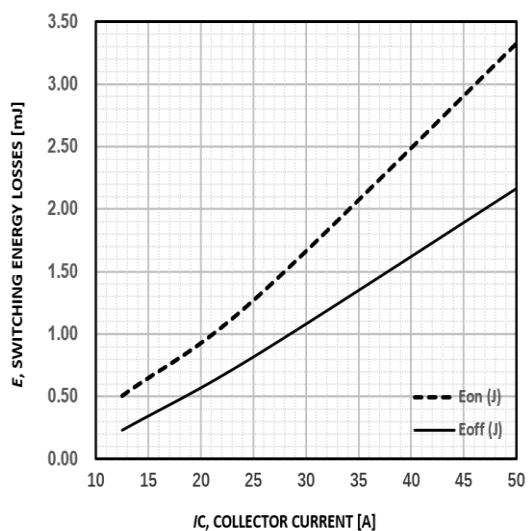


Figure 11. Typical energy loss VS.  $I_C$ ,  $T_C=25^\circ\text{C}$ ,  
 $V_{CE}=600\text{V}$ ,  $V_{GE}=15\text{V}$ ,  $R_g=15\Omega$

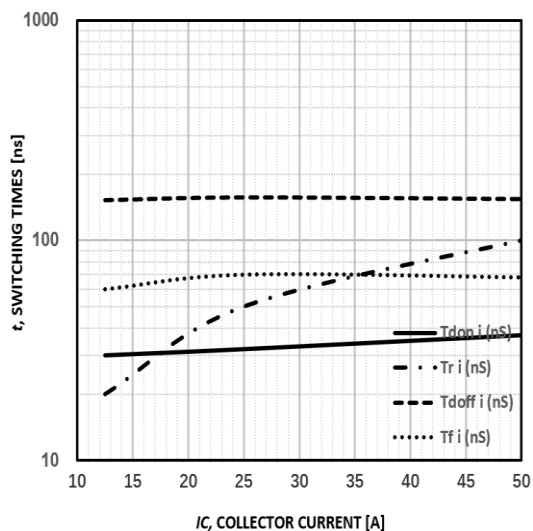


Figure 12. Typical switching time VS.  $I_C$ ,  $T_C=25^\circ\text{C}$ ,  
 $V_{CE}=600\text{V}$ ,  $V_{GE}=15\text{V}$ ,  $R_g=15\Omega$

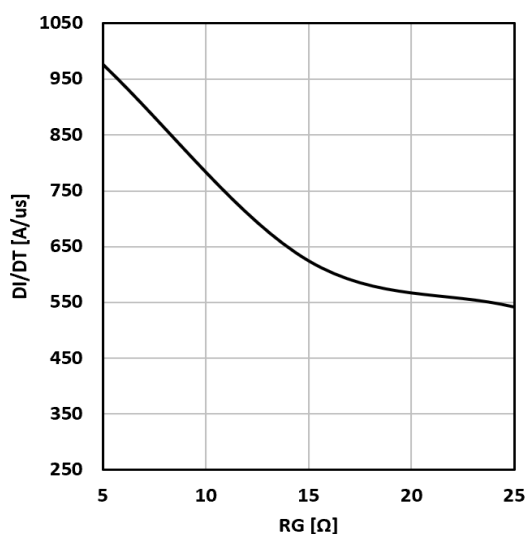


Figure 13. Typical diode di/dt vs rg Tc=25°C  
VCE=600V VGE=15V IF=25A

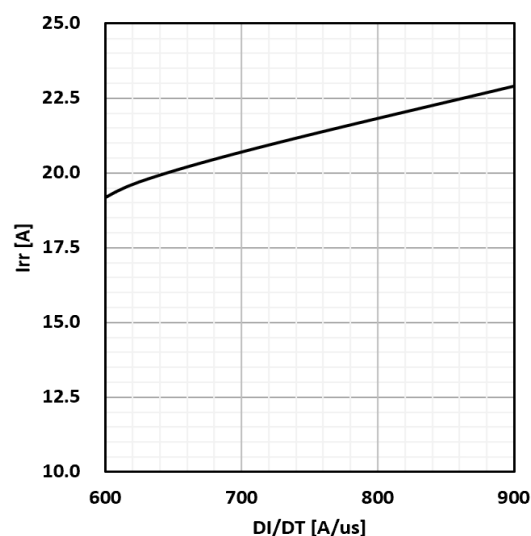


Figure 14. Typical diode irr vs di/dt Tc=25°C  
VCE=600V VGE=15V IF=25A

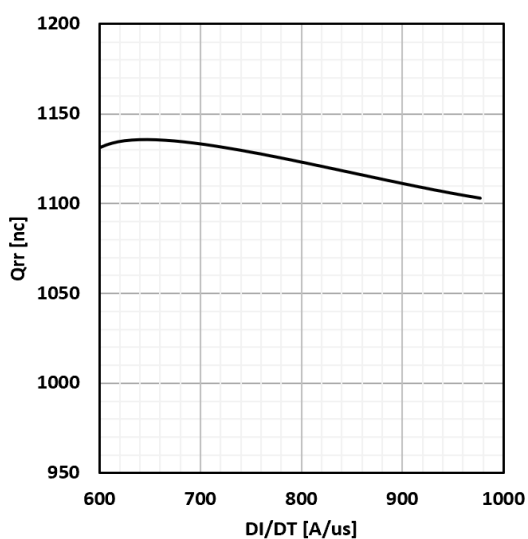


Figure 15. Typical diode Qrr vs di/dt Tc=25°C  
VCE=600V VGE=15V IF=25A

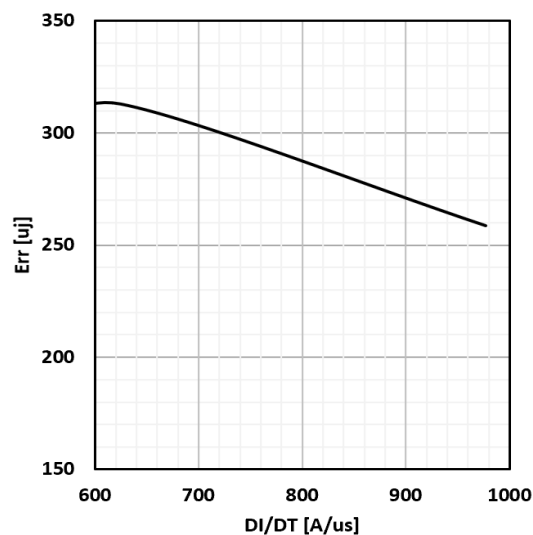


Figure 16. Typical diode Err vs di/dt Tc=25°C  
VCE=600V VGE=15V IF=25A

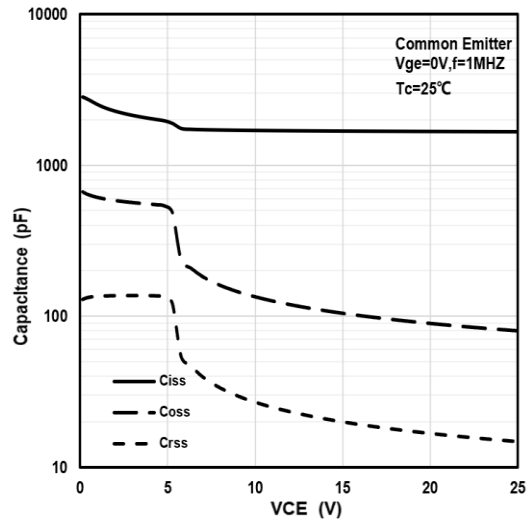


Figure 17. Typical capacitance VS. VCE,  
VGE=0V, f=1MHz

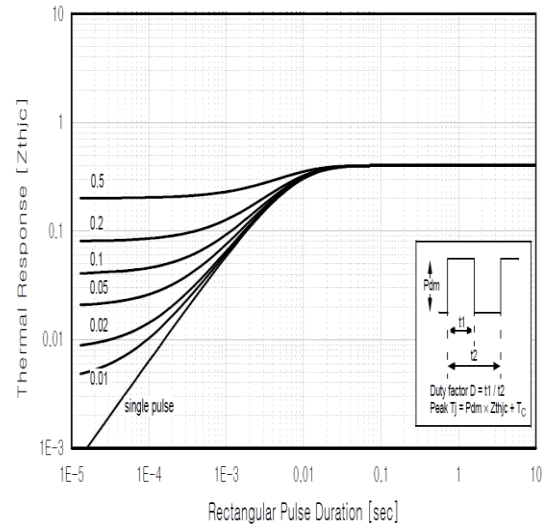
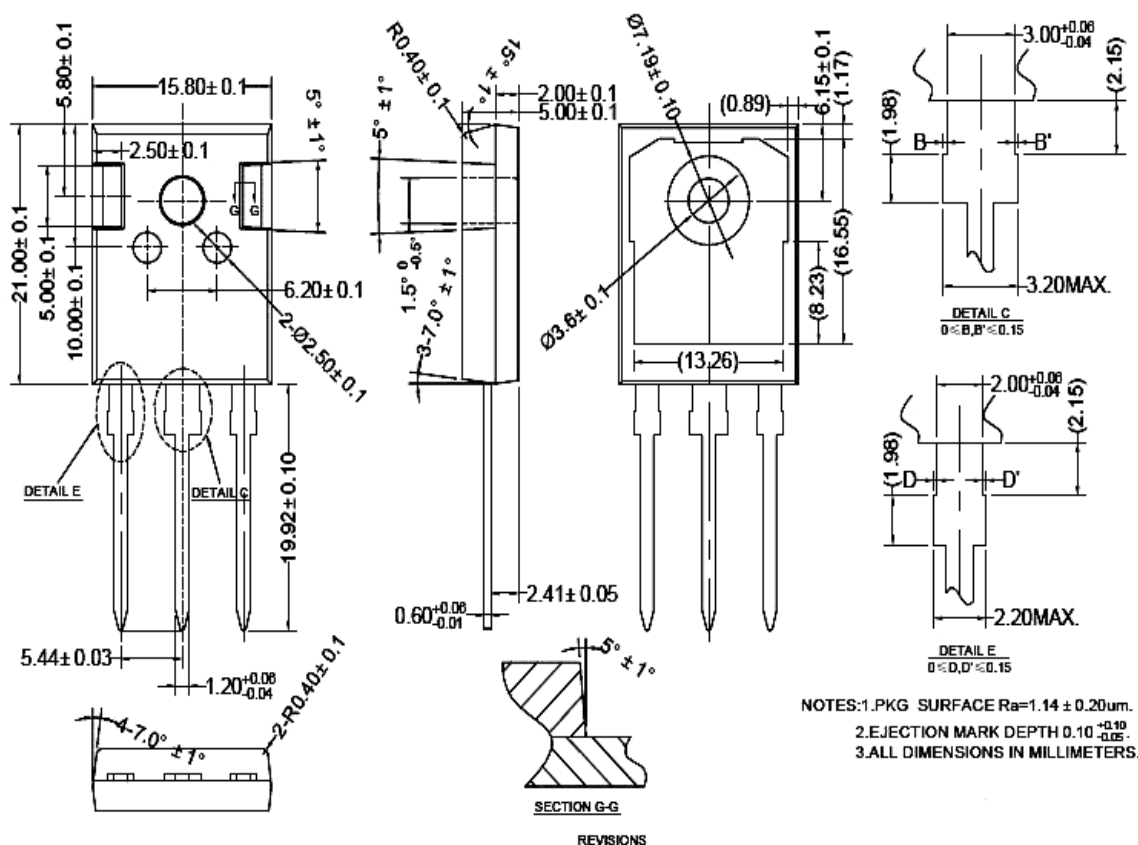


Figure 18. normalized transient thermal impedance,  
junction-to-case

## TO247 PACKAGE OUTLINE



公差标注	公差值	表面粗糙度
0	±0.2	Ra3.2~6.3
0.0	±0.1	Ra1.6~3.2
0.00	±0.01	Ra0.8~1.6
0.000	±0.005	Ra0.4~0.8
0.0000	±0.002	Ra0.2~0.4

0 ≤ D, D' ≤ 0.15

NOTES: 1. PKG SURFACE Ra=1.14 ± 0.20µm.  
2. EJECTION MARK DEPTH 0.10 <sup>+0.10</sup>/<sub>-0.05</sub>.  
3. ALL DIMENSIONS IN MILLIMETERS.



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